2019 IEEE INTERNATIONAL WORKSHOP ON

Metrology for ReroSpace

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CALL FOR PAPERS

for the Special Session on

MEASUREMENT FOR IMPROVING QUALITY, RELIABILITY AND SAFETY IN AEROSPACE APPLICATIONS

ABSTRACT

This Special Session represents an interesting opportunity for engineers and researchers to provide an increasing of knowledge and an easier diffusion of the most recent developments in the field of the measurement related to Quality, Reliability And Safety in aerospace applications.

TOPICS

Perspective authors can provide original contributions in this topic which can cover, but not only, the following aspects:

MetroAeroSpace 2019

- Measurements and techniques for Fault diagnosis
- Design and implementation of laboratory tests (Reliability test, Environmental test, Burn-in test, quality tests, etc.) and Qualification tests for components and systems
- Instrumentation and measurement methods for Testing and Diagnostics (Destructive and Nondestructive Testing, Vibration monitoring, Built-in Test Equipment and Automatic Test Equipment, etc.)
- Measurements, methods and instrumentation for evaluation of Reliability, Availability, Maintainability and Safety (RAMS)

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ABOUT THE CONVENERS

Lorenzo Ciani received the M.S. degree in electronic engineering and the Ph.D. degree in industrial and reliability engineering from the University of Florence, Italy, in 2005 and 2009, respectively.

He is currently an Assistant Professor with the Department of Information Engineering, University of Florence. He has authored or co-authored more than 120 peer-reviewed journal and conference papers.

Dr. Ciani is a member of the IEEE IMS TC-32 Fault Tolerant Measurement Systems and an Associate Editor of the IEEE ACCESS and the IEEE TRANSACTION ON INSTRUMENTATION AND MEASUREMENT. He received the 2015 IEEE I&M Outstanding Young Engineer Award for "his contribution to the advancement of instrumentation and measurement in the field of reliability analysis."

Marcantonio Catelani received the M.S. degree in electronic engineering from the University of Florence, Florence, Italy.

He is currently a Full Professor with the Department of Information Engineering, University of Florence. His current research interests include reliability, availability, maintainability, and safety (RAMS) context, the development of test profiles used for both the characterization and the evaluation of reliability performance, the development of new degradation models able to estimate the life cycle of electronic components, the development of automatic measurement system, the characterization of analog to digital converter converters, and quality control and related statistical methods.



